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## Supporting Information

## Ce Dopant Effects on $\mathrm{NaYF}_{4}$ Particle Morphology and Optical Properties

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Figure S1. TEM images of N-NPs with Ce concentration of (a) 20 and (b) $50 \mathrm{~mol} \%$. The size distribution of particles is given in the images.


Figure S2. Average longitudinal dimension and aspect ratio of N-NPs with Ce concentrations from 0 to $50 \mathrm{~mol} \%$.


Figure S3. Size distributions of N-NPs with Ce concentration from 0 to $50 \mathrm{~mol} \%$.


Figure S4. SEM images of N-MPs with Ce concentration of (a) 2 and (b) $5 \mathrm{~mol} \%$. The
distribution of the longitudinal dimension of particles is given in the images.

Table S1. EDX analysis results of N-MPs-Ce10, N-MPs-Ce20 and N-MPs-Ce50.

|  | $\begin{gathered} \mathrm{Na} \\ (\mathrm{at} \%) \end{gathered}$ | $\begin{gathered} \mathbf{Y} \\ (\mathbf{a t \%}) \end{gathered}$ | $\begin{gathered} \text { F } \\ (\mathbf{a t \%} \%) \end{gathered}$ | $\begin{gathered} \mathrm{Ce} \\ (\mathbf{a t \%} \% \end{gathered}$ | $\begin{gathered} \text { Yb } \\ (\mathbf{a t \%}) \end{gathered}$ | $\begin{gathered} \text { Er } \\ (\mathbf{a t \%}) \end{gathered}$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| N-MPs-Ce10 | 11.5 | 13.4 | 66.1 | 2.9 | 5.5 | 0.5 |
| N-MPs-Ce20-microparticle | 18.6 | 7.3 | 65.5 | 4.4 | 3.8 | 0.4 |
| N-MPs-Ce20-submicroparticle | 0.0 | 0.0 | 68.4 | 29.7 | 1.8 | 0.1 |
| N-MPs-Ce50-microparticle | 7.6 | 5.5 | 67.5 | 14.3 | 4.7 | 0.5 |
| N-MPs-Ce50-submicroparticle | 0.0 | 0.0 | 69.1 | 28.9 | 1.5 | 0.4 |



Figure S5. EDX image mapping of N-MPs-Ce50 at different regions: (a) region of microparticle; (b) region of submicroparticles.


Figure S6. The calculated grain size ( $\mathrm{a}, \mathrm{c}$ ) using the Scherrer equation and intensity ratio of (110) to (101) planes (b, d) from XRD patterns of N-MPs (a, b) and N-NPs (c, d) with Ce-doping concentration ranging from 0 to $50 \mathrm{~mol} \%$.


Figure S7. Up-conversion visible (a, c) and down-shifting infrared emissions (b, d) of N-MPs (a, b) and N-NPs (c, d).

Table S2. The fitted decay constants of time resolved emission spectra at 1530 nm for N -MPs and N -NPs using a double exponential equation.

| N-MPs | $\tau_{1}(\mu \mathrm{~s})$ | Standard | $\tau_{2}(\mu \mathrm{~s})$ | Standard | $\mathrm{N}-\mathrm{NPs}$ | $\tau_{1}(\mu \mathrm{~s})$ | Standard | $\tau_{2}(\mu \mathrm{~s})$ | Standard |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- |
|  |  | error |  | error |  |  | error |  | error |
| Ce 0 | 3741.8 | 14.1 | 3741.8 | 14.1 | Ce 0 | 342.8 | 4.4 | 2146.4 | 10.9 |
| Ce 2 | 3901.9 | 13.3 | 3901.9 | 13.3 | Ce 2 | 2213.9 | 10.7 | 353.7 | 5.6 |
| Ce 5 | 3932.7 | 13.1 | 3932.7 | 13.1 | Ce 5 | 433.4 | 12.0 | 2406.2 | 12.1 |
| Ce 10 | 3457.4 | 9.3 | 3457.4 | 9.3 | Ce 10 | 474.8 | 12.2 | 2480.4 | 13.8 |
| Ce 20 | 3115.5 | 7.3 | 3115.5 | 7.3 | Ce 20 | 1502.6 | $2.7 \mathrm{E}-6$ | 1502.6 | $2.7 \mathrm{E}-6$ |
| Ce 50 | 1692.4 | 3.2 | 1692.4 | 3.2 | Ce 50 | 939.5 | 6.0 | 213.3 | 2.8 |

